## Application/Control No. Applicant(s)/Patent Under Reexamination 10/053,576 TOMONARI ET AL Notic of References Cited Examiner Art Unit Page 1 of 1 Thomas M. Dougherty 2834 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY \* 05-2002 Hierold, Christofer 251/129.04 US-6,382,588 B1 Α 417/413.3 US-6,168,395 B1 01-2001 Quenzer et al. В \* US-6,557,820 B2 05-2003 Wetzel et al. 251/30.02 С \* 08-1995 Bonne et al. 216/2 US-5,441,597 A D US-6,626,417 B2 09-2003 Winger et al. 251/129.06 E 11-2003 347/54 F US-6,644,786 B1 Lebens, John A. \* 05-2002 G US-6,384,509 B1 Tomonari et al. 310/307 USн US-1 US-J K US-US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY 09-1997 Yamagishi et al. F16K 31/02 Ν JP-9-22022 Japan JP-2001-153252 06-2001 Kamakura et al. F16K 31/02 0 Japan 11-2001 Ρ JP-2000-317897 Japan Yoshida et al. B81B 3/00 Q JP-2000-309000 11-2000 Japan Tomanari et al. B81B 3/00 R s Т NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.